

<b>Notice of References Cited</b>	Application/Control No. 10/542,780		Applicant(s)/Patent Under Reexamination TAKI, TETSUYA	
	Examiner David Goodwin		Art Unit 2818	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0017061	01-2006	Sakamoto et al.	257/103
*	B	US-2005/0269584	12-2005	Hasegawa et al.	257/094
*	C	US-2005/0205881	09-2005	Yamazoe et al.	257/085
*	D	US-6,242,764	06-2001	Ohba et al.	257/190
*	E	US-2005/0145860	07-2005	Tanizawa, Koji	257/085
*	F	US-2002/0190263	12-2002	Hata et al.	257/103
*	G	US-2002/0104997	08-2002	Kuo et al.	257/79
*	H	US-6,064,079	05-2000	Yamamoto et al.	257/101
*	I	US-6,686,608	02-2004	Takahira, Yoshiyuki	257/96
*	J	US-6,841,800	01-2005	Oku et al.	257/94
*	K	US-5,970,080	10-1999	Hata, Toshio	372/45.01
*	L	US-2002/0014632	02-2002	Kaneyama et al.	257/103
*	M	US-6,872,986	03-2005	Fukuda et al.	257/101

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.